Search Notes



Application/Control No.	Applicant(s)/Patent under Reexamination	
10/629,866	LEE ET AL.	
Examiner	Art Unit	
Daniel Kim	2185	

SEARCHED					
Class	Subclass	Date	Examiner		
711	100, 101	3/22/2007	DK		
711	115	3/22/2007	DK		
710	5, 6	3/22/2007	DK		
710	58, 305	3/22/2007	DK		
439	631	3/22/2007	, DK		
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
711	115	3/22/2007	DK	
US PGPub Search		3/22/2007	DK	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
Updated EAST Search	3/22/2007	DK		
Inventor Name Search for DP	3/22/2007	DK		
IEEE Search	3/22/2007	DK		
ACM Search	3/22/2007	DK		
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